

RELIABILITY REPORT
FOR
MAX98304EWL+T
WAFER LEVEL PRODUCTS

May 9, 2011

MAXIM INTEGRATED PRODUCTS

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Conclusion

The MAX98304EWL+T successfully meets the quality and reliability standards required of all Maxim products. In addition, Maxim's continuous reliability monitoring program ensures that all outgoing product will continue to meet Maxim's quality and reliability standards.

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I. Device Description

A. General

The MAX98304 mono 3.2W Class D amplifier provides Class AB audio performance with Class D efficiency. This device offers five selectable gain settings (0dB, 3dB, 6dB, 9dB, and 12dB) set by a single gain-select input (GAIN). Active emissions-limiting, edge-rate, and overshoot control circuitry greatly reduces EMI. A filterless spread-spectrum modulation scheme eliminates the need for output filtering found in traditional Class D devices. These features reduce application component count. The IC's 0.95mA at 3.7V (1.2mA at 5V) quiescent current extends battery life in portable applications. The IC is available in a 9-bump (1.0mm x 1.0mm) WLP with 0.3mm pitch that is specified over the extended -40°C to +85°C temperature range.

II. Manufacturing Information

A. Description/Function:	Mono 3.2W Class D Amplifier
B. Process:	S18
C. Number of Device Transistors:	3445
D. Fabrication Location:	California
E. Assembly Location:	Japan and USA
F. Date of Initial Production:	September 24, 2010

III. Packaging Information

A. Package Type:	9-bump WLP 3x3 array
B. Lead Frame:	N/A
C. Lead Finish:	N/A
D. Die Attach:	N/A
E. Bondwire:	N/A (N/A mil dia.)
F. Mold Material:	N/A
G. Assembly Diagram:	#05-9000-4206
H. Flammability Rating:	Class UL94-V0
I. Classification of Moisture Sensitivity per JEDEC standard J-STD-020-C	Level 1
J. Single Layer Theta Ja:	°C/W
K. Single Layer Theta Jc:	°C/W
L. Multi Layer Theta Ja:	94°C/W
M. Multi Layer Theta Jc:	°C/W

IV. Die Information

A. Dimensions:	39.37 X 39.37 mils
B. Passivation:	Si ₃ N ₄ /SiO ₂ (Silicon nitride/ Silicon dioxide)
C. Interconnect:	Al with Ti/TiN Barrier
D. Backside Metallization:	None
E. Minimum Metal Width:	0.18µm
F. Minimum Metal Spacing:	0.18µm
G. Bondpad Dimensions:	
H. Isolation Dielectric:	SiO ₂
I. Die Separation Method:	Wafer Saw

V. Quality Assurance Information

- A. Quality Assurance Contacts: Richard Aburano (Manager, Reliability Engineering)
Don Lipps (Manager, Reliability Engineering)
Bryan Preeshl (Vice President of QA)
- B. Outgoing Inspection Level: 0.1% for all electrical parameters guaranteed by the Datasheet.
0.1% For all Visual Defects.
- C. Observed Outgoing Defect Rate: < 50 ppm
- D. Sampling Plan: Mil-Std-105D

VI. Reliability Evaluation

A. Accelerated Life Test

The results of the 135°C biased (static) life test are shown in Table 1. Using these results, the Failure Rate (λ) is calculated as follows:

$$\lambda = \frac{1}{\text{MTTF}} = \frac{1.83}{192 \times 4340 \times 48 \times 2} \quad (\text{Chi square value for MTTF upper limit})$$

(where 4340 = Temperature Acceleration factor assuming an activation energy of 0.8eV)

$$\lambda = 22.9 \times 10^{-9}$$

$$\lambda = 22.9 \text{ F.I.T. (60\% confidence level @ 25°C)}$$

The following failure rate represents data collected from Maxim's reliability monitor program. Maxim performs quarterly life test monitors on its processes. This data is published in the Reliability Report found at <http://www.maxim-ic.com/qa/reliability/monitor>. Cumulative monitor data for the S18 Process results in a FIT Rate of 0.40 @ 25C and 6.96 @ 55C (0.8 eV, 60% UCL)

B. E.S.D. and Latch-Up Testing (lot SQ2ZAQ001B, D/C 1003)

The AX46 die type has been found to have all pins able to withstand a HBM transient pulse of +/- 1500V per JEDEC JESD22-A114. Latch-Up testing has shown that this device withstands a current of +/- 100mA and overvoltage per JEDEC JESD78.

Table 1
Reliability Evaluation Test Results

MAX98304EWL+T

TEST ITEM	TEST CONDITION	FAILURE IDENTIFICATION	SAMPLE SIZE	NUMBER OF FAILURES	COMMENTS
Static Life Test (Note 1)	Ta = 135°C Biased Time = 192 hrs.	DC Parameters & functionality	48	0	SQ2ZAQ001B, D/C 1003

Note 1: Life Test Data may represent plastic DIP qualification lots.